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I hereby certify that the attached Transmittal (1 page) and Response to the Final Office Action dated December 16, 2004 (4 pages) are submitted to the U.S. Patent and Trademark Office via facsimile (703-872-9306) on the date shown below. (Total 5 pages).

Date: March 16, 2005



Stormi R. Davis

RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2829

PATENT APPLICATION
Docket No.: 8750-017
Client Ref. No.: SPX200110-0010US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Sang-Eun LEE and Jae-Sung HAN

Serial No.: 10/068,152 Examiner: Hollington, Jermele M.

Filed: February 6, 2002 Group Art Unit: 2829

Confirmation No.: 7500

For: METHOD OF IDENTIFYING AND ANALYZING SEMICONDUCTOR
CHIP DEFECTS

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Responsive to the Final Office Action dated December 16, 2004, enclosed is an amendment in the above-identified application.

The fee has been calculated as shown below.

<u>CLAIMS AS AMENDED</u>					
For:	Number After Amendment	Previous Number	Extra	Rate	Additional Fee
Total Claims	10	21	0	x \$50 =	\$0
Independent Claims	1	4	0	x \$200 =	\$0
TOTAL ADDITIONAL FEE FOR THIS AMENDMENT					\$0

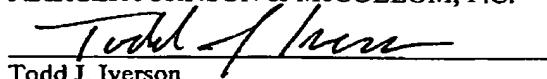
*greater of twenty (20) or number for which fee has been paid

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Respectfully submitted,
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SEMICONDUCTOR CHIP DEFECTSMail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450AMENDMENT AFTER FINAL REJECTION UNDER 37 CFR 1.116

This paper is responsive to the final Office Action, Paper No. 20041213, mailed on December 16, 2004.

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.